CMOS Dual Monostable Multivibrator

High-Voltage Types (20-Volt Rating)

The RCA-CD4098B dual monostable multivibrator provides stable retriggerable/resettable one-shot operation for any fixed-voltage timing application.

An external resistor (R_X) and an external capacitor (C_X) control the timing for the circuit. Adjustment of R_X and C_X provides a wide range of output pulse widths from the Q and $\overline{Q}$ terminals. The time delay from trigger input to output transition (trigger propagation delay) and the time delay from reset input to output transition (reset propagation delay) are independent of R_X and C_X.

Leading-edge-triggering (+TR) and trailing-edge-triggering (−TR) inputs are provided for triggering from either edge of an input pulse. An unused +TR input should be tied to V_{SS}. An unused −TR input should be tied to V_{DD}. A RESET (on low level) is provided for immediate termination of the output pulse or to prevent output pulses when power is turned on. An unused RESET input should be tied to V_{DD}. However, if an entire section of the CD4098B is not used, its RESET should be tied to V_{SS}. See Table I.

In normal operation the circuit triggers (extends the output pulse one period) on the application of each new trigger pulse. For operation in the non-retriggerable mode, $\overline{Q}$ is connected to −TR when leading-edge triggering (+TR) is used or Q is connected to +TR when trailing-edge triggering (−TR) is used.

The time period (T) for this multivibrator can be approximated by: $T_X = \frac{1}{2} R_X C_X$ for $C_X \geq 0.01\ \mu F$. Time periods as a function of R_X for values of C_X and V_{DD} are given in Fig. 8. Values of T vary from unit to unit and as a function of voltage, temperature, and $R_X C_X$.

The minimum value of external resistance, R_X, is 5 kΩ. The maximum value of external capacitance, C_X, is 100 μF. Fig. 9 shows time periods as a function of C_X for values of R_X and V_{DD}.

The output pulse width has variations of ±2.5% typically, over the temperature range of −55°C to 125°C for C_X=1000 pF and R_X=100 kΩ.

For power supply variations of ±5%, the output pulse width has variations of ±0.5% typically, for V_{DD}=10 V and 15 V and ±1% typically, for V_{DD}=5 V at C_X=1000 pF and R_X=5 kΩ.

These types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic package (E suffix), 16-lead ceramic flat packages (K suffix), and in chip form (H suffix).

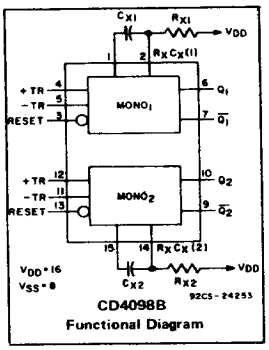
The CD4098B is similar to type MC14528.

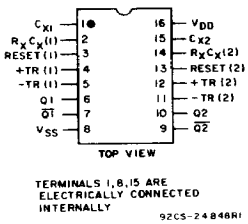
Features:

- **Retriggerable/resettable capability**
- **Trigger and reset propagation delays independent of R_X, C_X**
- **Triggering from leading or trailing edge**
- **Q and $\overline{Q}$ buffered outputs available**
- **Separate resets**
- **Wide range of output-pulse widths**
- **100% tested for maximum quiescent current at 20 V**
- **Maximum input current of 1 μA at 18 V over full package-temperature range; 100 nA at 18 V and 25°C**
- **Noise margin (full package-temperature range): 1 V at V_{DD}= 5 V; 2 V at V_{DD}=10 V; 2.5 V at V_{DD}=15 V**
- **5-V, 10-V, and 15-V parametric ratings**
- **Standardized, symmetrical output characteristics**
- **Meets all requirements of JEDEC Tentative Standard No. 13A, "Standard Specifications for Description of 'B' Series CMOS Devices."**

Applications:

- **Pulse delay and timing**
- **Pulse shaping**
- **Astable multivibrator**





TERMINAL ASSIGNMENT

MAXIMUM RATINGS, *Absolute-Maximum Values:*

DC SUPPLY-VOLTAGE RANGE, (V_{DD}) (Voltages referenced to V_{SS} Terminal)	−0.5 to +20 V
INPUT VOLTAGE RANGE, ALL INPUTS	−0.5 to V_{DD} +0.5 V
DC INPUT CURRENT, ANY ONE INPUT	±10 mA
POWER DISSIPATION PER PACKAGE (P_D)	
For T_A = −40 to +60°C (PACKAGE TYPE E)	500 mW
For T_A = +60 to +85°C (PACKAGE TYPE E)	Derate Linearly at 12 mW/°C to 200 mW
For T_A = −55 to +100°C (PACKAGE TYPES D, F, K)	500 mW
For T_A = +100 to +125°C (PACKAGE TYPES D, F, K)	Derate Linearly at 12 mW/°C to 200 mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR FOR T_A = FULL PACKAGE-TEMPERATURE RANGE (All Package Types)	100 mW
OPERATING-TEMPERATURE RANGE (T_A)	
PACKAGE TYPES D, F, K, H	−55 to +125°C
PACKAGE TYPE E	−40 to +85°C
STORAGE TEMPERATURE RANGE (T_{stg})	−65 to +150°C
LEAD TEMPERATURE (DURING SOLDERING) At distance 1/16 ± 1/32 inch (1.59 ± 0.79 mm) from case for 10 s max.	+265°C

RECOMMENDED OPERATING CONDITIONS

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	V_{DD} V	LIMITS MIN.	LIMITS MAX.	UNITS
Supply-Voltage Range (For T_A = Full Package-Temperature Range)	–	3	18	V
Trigger Pulse Width t_W(TR)	5 10 15	140 60 40	– – –	ns
Reset Pulse Width t_W(R) (This is a function of C_X)	–	See Dynamic Char. Chart and Fig. 10		–
Trigger Rise or Fall Time t_r(TR), t_f(TR)	5, 15	–	100	μs

TABLE I

CD4098B FUNCTIONAL TERMINAL CONNECTIONS

FUNCTION	V_{DD} TO TERM. NO.		V_{SS} TO TERM. NO.		INPUT PULSE TO TERM. NO.		OTHER CONNECTIONS	
	$MONO_1$	$MONO_2$	$MONO_1$	$MONO_2$	$MONO_1$	$MONO_2$	$MONO_1$	$MONO_2$
Leading-Edge Trigger/ Retriggerable	3, 5	11, 13			4	12		
Leading-Edge Trigger/ Non-retriggerable	3	13			4	12	5-7	11-9
Trailing-Edge Trigger/ Retriggerable	3	13	4	12	5	11		
Trailing-Edge Trigger/ Non-retriggerable	3	13			5	11	4-6	12-10
Unused Section	5	11	3, 4	12, 13				

NOTES:

1. A RETRIGGERABLE ONE-SHOT MULTIVIBRATOR HAS AN OUTPUT PULSE WIDTH WHICH IS EXTENDED ONE FULL TIME PERIOD (T_X) AFTER APPLICATION OF THE LAST TRIGGER PULSE. The minimum time between retriggering edges (or trigger and retrigger edges) is 40 per cent of (T_X).
2. A NON-RETRIGGERABLE ONE-SHOT MULTIVIBRATOR HAS A TIME PERIOD T_X REFERENCED FROM THE APPLICATION OF THE FIRST TRIGGER PULSE.

INPUT PULSE TRAIN

RETRIGGERABLE MODE PULSE WIDTH (+TR MODE)

NON-RETRIGGERABLE MODE PULSE WIDTH (+TR MODE)

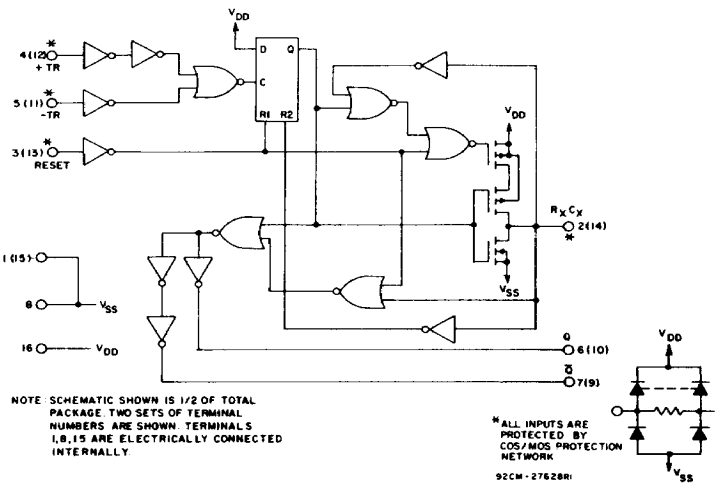


Fig. 4 – CD4098B logic diagram.

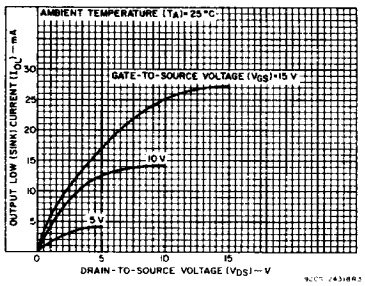


Fig. 1 – Typical output low (sink) current characteristics.

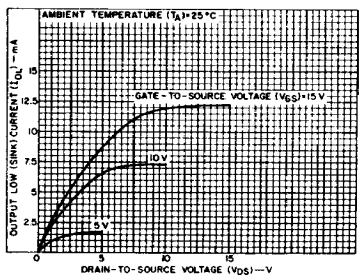


Fig. 2 – Minimum output low (sink) current characteristics.

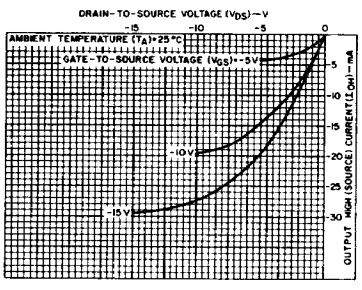


Fig. 3 – Typical output high (source) current characteristics.

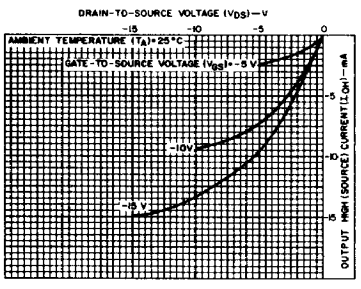


Fig. 5 – Minimum output high (source) current characteristics.

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C) Values at -55, +25, +125 Apply to D, F, K, H, pkgs. Values at −40,+25,+85 Apply to E Pkgs.							UNITS
								+25			
	V_O (V)	V_{IN} (V)	V_{DD} (V)	−55	−40	+85	+125	Min.	Typ.	Max.	
Quiescent Device Current I_{DD} Max.	–	0,5	5	1	1	30	30	–	0.02	1	μA
	–	0,10	10	2	2	60	60	–	0.02	2	
	–	0,15	15	4	4	120	120	–	0.02	4	
	–	0,20	20	20	20	600	600	–	0.04	20	
Output Low (Sink) Current, I_{OL} Min.	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	–	mA
	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	–	
	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	–	
Output High (Source) Current, I_{OH} Min.	4.6	0,5	5	−0.64	−0.61	−0.42	−0.36	−0.51	−1	–	
	2.5	0,5	5	−2	−1.8	−1.3	−1.15	−1.6	−3.2	–	
	9.5	0,10	10	−1.6	−1.5	−1.1	−0.9	−1.3	−2.6	–	
	13.5	0,15	15	−4.2	−4	−2.8	−2.4	−3.4	−6.8	–	
Output Voltage: Low-Level, V_{OL} Max.	–	0,5	5	0.05				–	0	0.05	V
	–	0,10	10	0.05				–	0	0.05	
	–	0,15	15	0.05				–	0	0.05	
Output Voltage: High-Level, V_{OH} Min.	–	0,5	5	4.95				4.95	5	–	
	–	0,10	10	9.95				9.95	10	–	
	–	0,15	15	14.95				14.95	15	–	
Input Low Voltage, V_{IL} Max.	0.5,4.5	–	5	1.5				–	–	1.5	V
	1,9	–	10	3				–	–	3	
	1.5,13.5	–	15	4				–	–	4	
Input High Voltage, V_{IH} Min.	0.5,4.5	–	5	3.5				3.5	–	–	
	1,9	–	10	7				7	–	–	
	1.5,13.5	–	15	11				11	–	–	
Input Current, I_{IN} Max.	–	0,18	18	±0.1	±0.1	±1	±1	–	$\pm 10^{-5}$	±0.1	μA
Output Leakage I_{OUT} Max.	0,18	0,18	18	±0.4	±0.4	±12	±12	–	$\pm 10^{-4}$	±0.4	μA

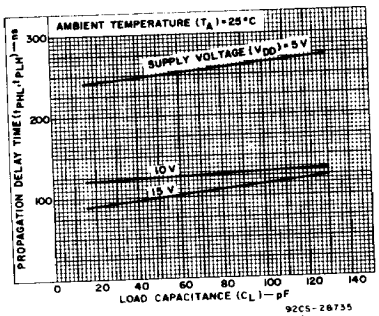


Fig. 6 – Typical propagation delay time vs. load capacitance, trigger into Q out. (All values of C_X and R_X.)

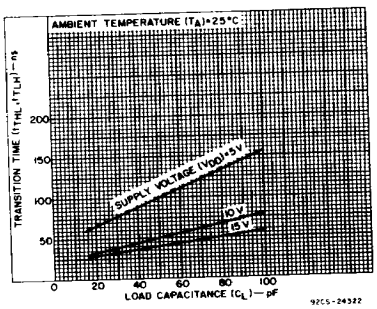


Fig. 7 – Transition time vs. load capacitance for R_X = 5 kΩ-10000 kΩ and C_X = 15 pF-10000 pF.

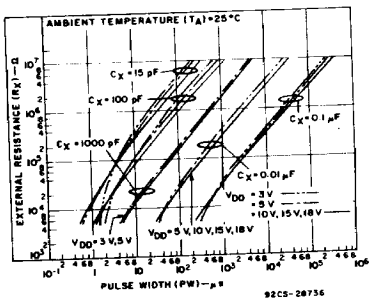


Fig. 8 – Typical external resistance vs. pulse width.

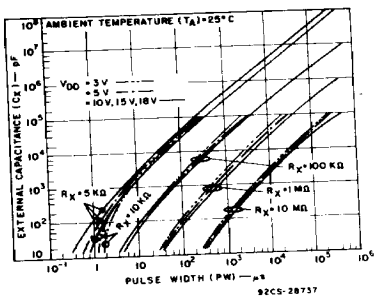


Fig. 9 – Typical external capacitance vs. pulse width.

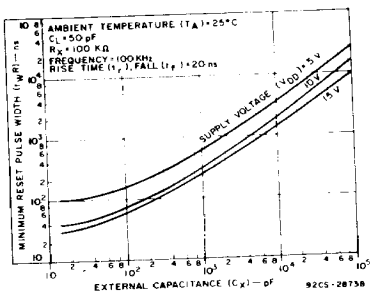


Fig. 10 – Typical minimum reset pulse width vs. external capacitance.

DYNAMIC ELECTRICAL CHARACTERISTICS

At $T_A = 25°C$; Input $t_r, t_f = 20$ ns, $C_L = 50$ pF, $R_L = 200$ kΩ

CHARACTERISTIC	TEST CONDITIONS			LIMITS		UNITS
	R_X (kΩ)	C_X (pF)	V_{DD} (V)	Typ.	Max.	
Trigger Propagation Delay Time +TR, −TR to Q, $\overline{Q}$ t_{PHL}, t_{PLH}	5 to 10,000	≥15	5	250	500	ns
			10	125	250	
			15	100	200	
Minimum Trigger Pulse Width, t_{WH}, t_{WL}	5 to 10,000	≥15	5	70	140	ns
			10	30	60	
			15	20	40	
Transition Time, t_{TLH}	5 to 10,000	≥15	5	100	200	ns
			10	50	100	
			15	40	80	
t_{THL}	5 to 10,000	15 to 10,000	5	100	200	
			10	50	100	
			15	40	80	
	5 to 10,000	0.01 μF to 0.1 μF	5	150	300	
			10	75	150	
			15	65	130	
	5 to 10,000	0.1 μF to 1 μF	5	250	500	
			10	150	300	
			15	80	160	
Reset Propagation Delay Time, T_{PHL}, T_{PLH}	5 to 10,000	≥15	5	225	450	ns
			10	125	250	
			15	75	150	
Minimum Reset Pulse Width, $t_W R$	100	15	5	100	200	ns
			10	40	80	
			15	30	60	
		1000	5	600	1200	
			10	300	600	
			15	250	500	
		0.1 μF	5	25	50	μs
			10	15	30	
			15	10	20	
Trigger Rise or Fall Time t_r(TR), t_f(TR)	–	–	5 to 15	–	100	μs
Pulse Width Match Between Circuits in Same Package	10	10,000	5	5	10	%
			10	7.5	15	
			15	7.5	15	
Input Capacitance, C_{IN}	Any Input			5	7.5	pF

TEST CIRCUITS

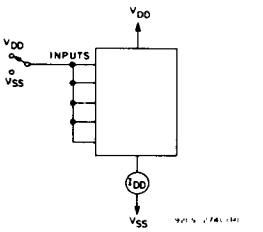


Fig. 12 – Quiescent-device-current test circuits.

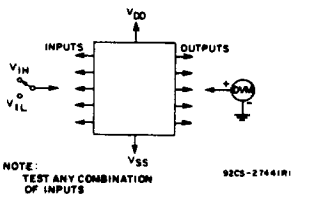


Fig. 13 – Input-voltage test circuit.

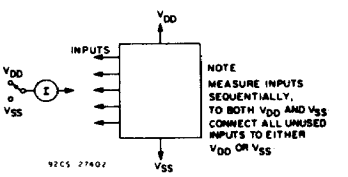


Fig. 14 – Input leakage current test circuit.

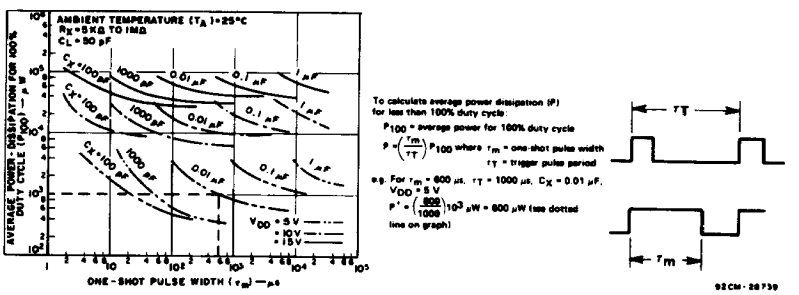


Fig. 11 – Average power dissipation vs. one-shot pulse width.

APPLICATIONS

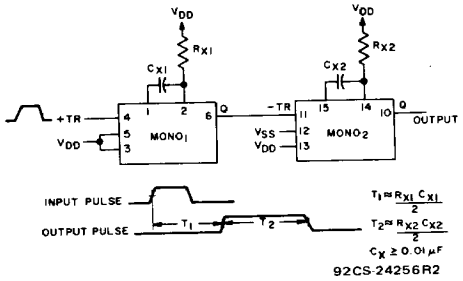
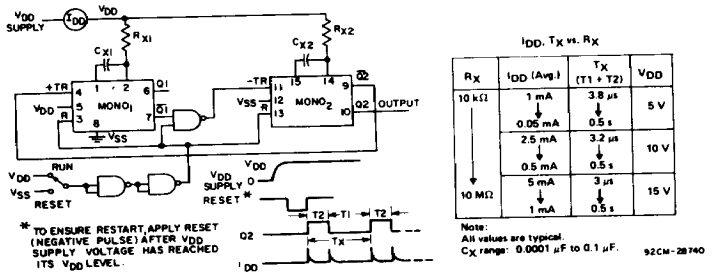


Fig. 15 – Pulse delay.



I_{DD}, T_X vs. R_X

R_X	I_{DD} (Avg.)	T_X (T1 + T2)	V_{DD}
10 kΩ	1 mA	3.8 µs	5 V
	0.05 mA	0.5 s	
	2.5 mA	3.2 µs	10 V
	0.5 mA	0.5 s	
	5 mA	3 µs	15 V
10 MΩ	1 mA	0.5 s	

Note:
All values are typical.
C_X range: 0.0001 µF to 0.1 µF.

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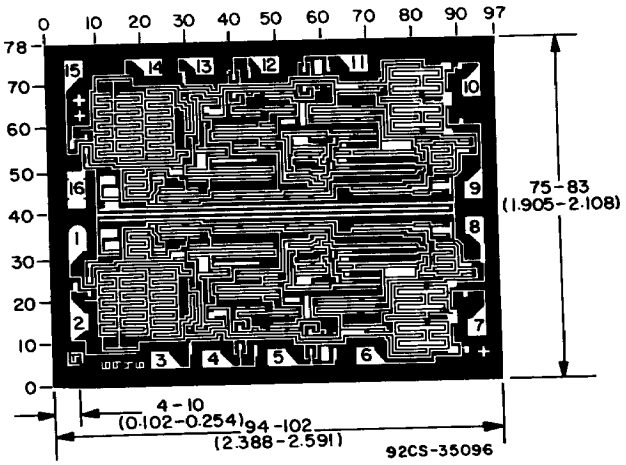
Fig. 16 – Astable multivibrator with restart after reset capability.



Dimensions and Pad Layout for CD4098BH

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

The photographs and dimensions of each CMOS chip represent a chip when it is part of the wafer. When the wafer is separated into individual chips, the angle of cleavage may vary with respect to the chip face for different chips. The actual dimensions of the isolated chip, therefore, may differ slightly from the nominal dimensions shown. The user should consider a tolerance of −3 mils to +16 mils applicable to the nominal dimensions shown.